TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSIV)

2SK3564

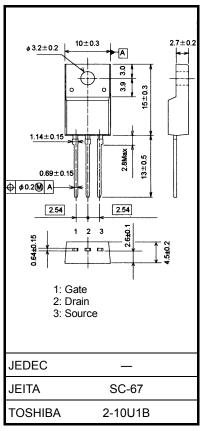
Switching Regulator Applications

Unit: mm

- Low drain-source ON resistance: RDS (ON) = 3.7Ω (typ.)
- High forward transfer admittance: $|Y_{fs}| = 2.6 \text{ S (typ.)}$
- Low leakage current: $I_{DSS} = 100 \, \mu \, A \, (V_{DS} = 720 \, V)$
- Enhancement mode: $V_{th} = 2.0 \sim 4.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

| Characteristics | | Symbol | Rating | Unit | |
|--|------------------------------|------------------|---------|------|--|
| Drain-source voltage | | V_{DSS} | 900 | V | |
| Drain-gate voltage ($R_{GS} = 20 \text{ k}\Omega$) | | V_{DGR} | 900 | V | |
| Gate-source voltage | | V_{GSS} | ±30 | V | |
| Drain current | DC (Note 1) | I _D | 3 | | |
| | Pulse (t = 1 ms) (Note 1) | I _{DP} | 9 | Α | |
| Drain power dissipation (Tc = 25°C) | | PD | 40 | W | |
| Single pulse avalanche energy (Note 2) | | E _{AS} | 408 | mJ | |
| Avalanche current | | I _{AR} | 3 | Α | |
| Repetitive avalanche energy (Note 3) | | E _{AR} | 4.0 | mJ | |
| Channel temperature | | T _{ch} | 150 | °C | |
| Storage temperature range | | T _{stg} | -55~150 | °C | |

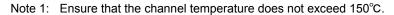


Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

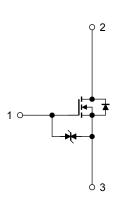
| Characteristics | Symbol | Max | Unit |
|--|------------------------|-------|------|
| Thermal resistance, channel to case | R _{th (ch-c)} | 3.125 | °C/W |
| Thermal resistance, channel to ambient | R _{th (ch-a)} | 62.5 | °C/W |



Note 2:
$$V_{DD} = 90 \text{ V}$$
, $T_{ch} = 25^{\circ}\text{C}$, $L = 83 \text{ mH}$, $I_{AR} = 3.0 \text{ A}$, $R_G = 25 \Omega$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Please handle with caution.



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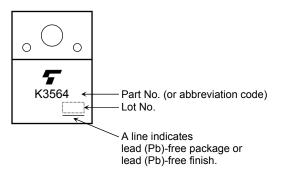
Electrical Characteristics (Ta = 25°C)

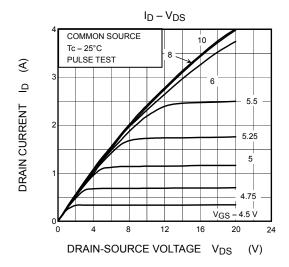
| Char | acteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|------------------------------|----------------|----------------------|--|------|------|-----|------|
| Gate leakage cui | rent | I _{GSS} | $V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$ | _ | _ | ±10 | μА |
| Gate-source brea | akdown voltage | V (BR) GSS | $I_G = \pm 10 \ \mu A, \ V_{DS} = 0 \ V$ | ±30 | _ | _ | V |
| Drain cut-off curr | ent | I _{DSS} | V _{DS} = 720 V, V _{GS} = 0 V | _ | _ | 100 | μА |
| Drain-source bre | akdown voltage | V (BR) DSS | I _D = 10 mA, V _{GS} = 0 V | 900 | _ | _ | V |
| Gate threshold ve | oltage | V _{th} | V _{DS} = 10 V, I _D = 1 mA | 2.0 | | 4.0 | V |
| Drain-source ON | resistance | R _{DS} (ON) | V _{GS} = 10 V, I _D = 1.5 A | _ | 3.7 | 4.3 | Ω |
| Forward transfer | admittance | Y _{fs} | V _{DS} = 20 V, I _D = 1.5 A | 0.65 | 2.6 | _ | S |
| Input capacitance | | C _{iss} | V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz | _ | 700 | _ | pF |
| Reverse transfer capacitance | | C _{rss} | | _ | 15 | _ | |
| Output capacitance | | C _{oss} | | _ | 75 | _ | |
| Switching time | Rise time | t _r | V_{GS} V_{OD} | _ | 20 | _ | |
| | Turn-on time | t _{on} | | _ | 60 | _ | |
| | Fall time | t _f | | _ | 35 | _ | ns |
| | Turn-off time | t _{off} | Duty \leq 1%, $t_W = 10 \mu s$ | _ | 125 | _ | |
| Total gate charge | | Qg | | _ | 17 | _ | |
| Gate-source charge | | Q _{gs} | $V_{DD} \simeq 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}$ | _ | 10 | _ | nC |
| Gate-drain charge | | Q _{gd} | | _ | 7 | | |

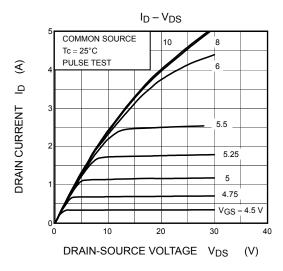
Source-Drain Ratings and Characteristics (Ta = 25°C)

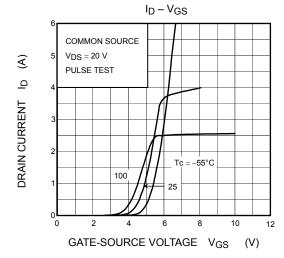
| Characteristics | Symbol | Test Condition | Min | Тур. | Max | Unit |
|---|------------------|---|-----|------|------|------|
| Continuous drain reverse current (Note 1) | I _{DR} | _ | _ | _ | 3 | Α |
| Pulse drain reverse current (Note 1) | I _{DRP} | _ | _ | _ | 9 | Α |
| Forward voltage (diode) | V _{DSF} | $I_{DR} = 3 A$, $V_{GS} = 0 V$ | _ | _ | -1.9 | V |
| Reverse recovery time | t _{rr} | $I_{DR} = 3 \text{ A}, V_{GS} = 0 \text{ V},$ | _ | 850 | _ | ns |
| Reverse recovery charge | Q _{rr} | dl _{DR} /dt = 100 A/μs | _ | 4.7 | _ | μС |

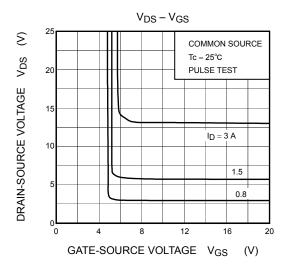
Marking

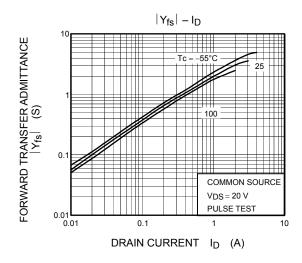


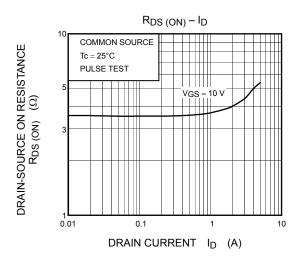




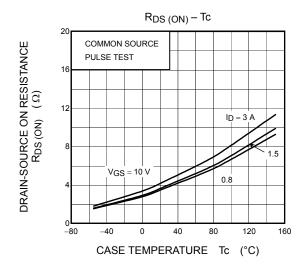


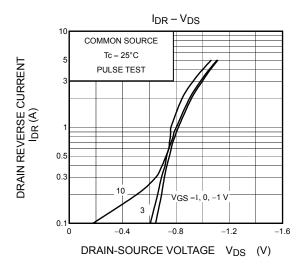


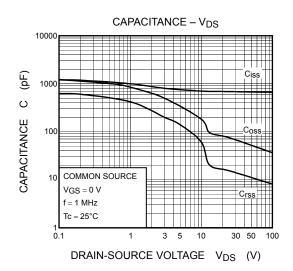


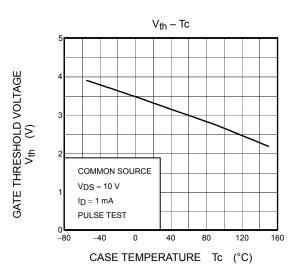


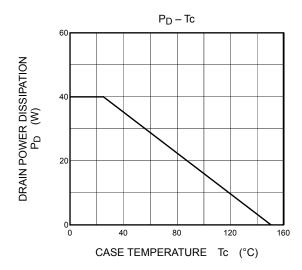
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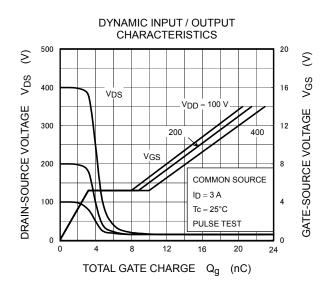


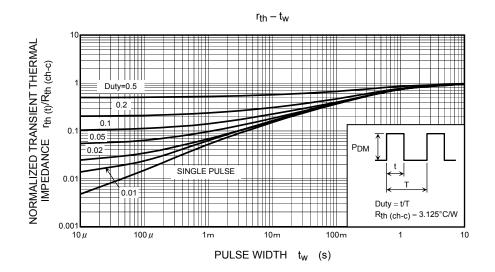


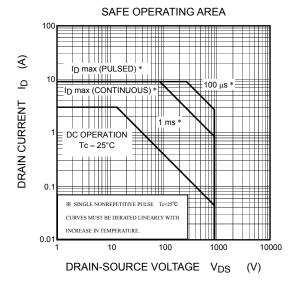


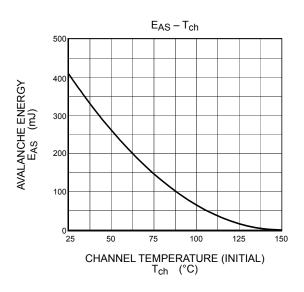


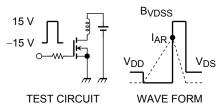












$$R_G = 25 \Omega$$

$$V_{DD} = 90 \text{ V, L} = 83\text{mH}$$

$$E_{AS} = \frac{1}{2} \cdot \text{L} \cdot \text{I}^2 \cdot \left(\frac{\text{BVDSS}}{\text{BVDSS} - \text{VDD}}\right)$$

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20070701-EN

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